

Laser Diode Test System (ATE-LD-5A)

Laser Diode Reliability & Burn-In Test System





The ATE Laser Diode Test System provides a low cost, high performance, accelerated aging, burn-in, and qualification testing for laser diodes. The PRT uses precise control allowing the user to test 64 to 1024 laser diodes in humidity, subzero & high temperature conditions.

Affordable & High Performance

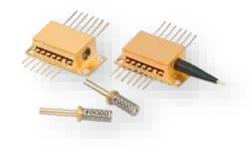
Powerful Software Interface

- An easy to use GUI provides real-time testing and functional reports
- Multiple test scenarios (recipes) are easily configured without complicated programming.
- FIT (Failure in Time) & Mean Time to Failure (MTTF) calculation
- LIV Curve, Threshold Current, Operating Current, Forward Voltage, Monitoring Current and Data Collection
- Designed for use by Operators & Supervisors
- E-mail notification

Custom Interface Design

- Custom laser diode test fixture boards are built to meet your packaging & test specification
- Custom PRT system input and output interface board connections
- Custom interface control with third party environmental chambers
- Designed to operate up to 200°C





Technical Data

	FIT (Failure In Time),
	MTTF (Mean Time to Failure) ACC,
Reliability Test & Modes	APC, LIV
	LIV Curve, Threshold Current,
	Operating Current, Forward Voltage,
Measured Quantities	Monitoring Current, Vmax, Imax, Imin
Number Test Components	64 - 1024
Current Range	1mA – 5,000 mA
Current Accuracy	0.1% of Full Scale
Source Measure Board	Custom Interface Test Fixture
Current Sweep	0.1 mA to 200 mA (200 steps)
Maximum Current	5,000 mA
Default Current	
Measurement Resolution	Analog to Digital 13-bit
Scan Time	2 to 6 seconds per component
Input Voltage	110V -240V AC
Power Consumption	220 Watts
	L-515 x W-477 x H-395 (size based on
System Dimensions (mm)	64 component testing)
Material	Aluminum/Steel

Essential Features

Conforms to Test Standards

Telcordia (Bellcore) GR-468-CORE MIL-STD-883E, Test Method 1016

Types of Testing

Accelerated aging, burn-in, and qualification testing

Designed to Work with All Third-Party Environmental Test Chambers

HAST, HTOL, Autoclave, Sub-Zero & High Temperature & Humidity, Bias Test

Power Monitoring & UPS Backup

Power Failure mode ensures data integrity even through power blackouts

Laser Diode Protection

Custom current high/low limits are set to protect the laser from damage during burn-in or reliability testing



